

Docket No. 289855US0PCT

IAP15 Rec'd PCT/PTO 21 APR 2006

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

IN RE APPLICATION OF: Laurent LABROUSSE, et al.

SERIAL NO: New U.S PCT Application Based on PCT/FR04/50532

GAU:

FILED: Herewith

EXAMINER:

FOR: SUBSTRATE, IN PARTICULAR GLASS SUBSTRATE, SUPPORTING AT LEAST ONE STACK OF A PHOTOCATALYTIC LAYER AND A SUBLAYER FOR THE HETEROEPITAXIAL GROWTH OF SAID LAYER

INFORMATION DISCLOSURE STATEMENT UNDER 37 CFR 1.97

COMMISSIONER FOR PATENTS
ALEXANDRIA, VIRGINIA 22313

SIR:

Applicant(s) wish to disclose the following information.

REFERENCES

The applicant(s) wish to make of record the references cited in the International Search Report and listed on the attached form PTO-1449. Copies of the listed references are attached, where required, as are either statements of relevancy or any readily available English translations of pertinent portions of any non-English language references.

A check or credit card payment form is attached in the amount required under 37 CFR §1.17(p).

RELATED CASES

Attached is a list of applicant's pending application(s), published application(s) or issued patent(s) which may be related to the present application. In accordance with the waiver of 37 CFR 1.98 dated September 21, 2004, copies of the cited pending applications are not provided. Cited published and/or issued patents, if any, are listed on the attached PTO form 1449.

A check or credit card payment form is attached in the amount required under 37 CFR §1.17(p).

CERTIFICATION

Each item of information contained in this information disclosure statement was first cited in any communication from a foreign patent office in a counterpart foreign application not more than three months prior to the filing of this statement.

No item of information contained in this information disclosure statement was cited in a communication from a foreign patent office in a counterpart foreign application or, to the knowledge of the undersigned, having made reasonable inquiry, was known to any individual designated in 37 CFR §1.56(c) more than three months prior to the filing of this statement.

DEPOSIT ACCOUNT

Please charge any additional fees for the papers being filed herewith and for which no check or credit card payment is enclosed herewith, or credit any overpayment to deposit account number 15-0030. A duplicate copy of this sheet is enclosed.

Respectfully submitted,

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Form PTO 1449 (Modified)		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY DOCKET NO. 289855US0PCT		SERIAL NO. 10576724 New U.S PCT Application Based on PCT/FR04/50532	
LIST OF REFERENCES CITED BY APPLICANT		APPLICANT Laurent LABROUSSE, et al.		10576724 - GAU: 1793			
		FILING DATE Herewith		GROUP			
U.S. PATENT DOCUMENTS							
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
/D.L./	AA	2002/0045073	4/18/2002	FINLEY, James J. et al.			
	AB						
	AG						
	AD						
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	AG						
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	AI						
	AJ						
	AK						
	AL						
	AM						
	AN						
FOREIGN PATENT DOCUMENTS							
		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION		
YES	NO						
/D.L./	AD	03/009061	1/30/2003	WO			
	AP						
	AD						
	AP						
	AS						
	AT						
	AU						
	AV						
OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)							
/D.L./	AW	TAKAHASHI, T. et al., "Photocatalytic Properties of TiO ₂ /WO ₃ bilayers deposited by reactive sputtering", Journal of Vacuum Science and Technology, Vol. 21, No 4, Pages 1409-1413, 2003.					
/D.L./	AX	OKUDERA, H. et al., "Fabrication of silica-anatase multilayer coating on a K-Ca-Zn-Si glass substrate", Thin Solid Films, Vol. 441, Pages 50-55, 2003.					
	AY						
	AZ	<input type="checkbox"/> Additional References sheet(s) attached					
Examiner	/Diana Liao/			Date Considered 12/19/2008			

*Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.